

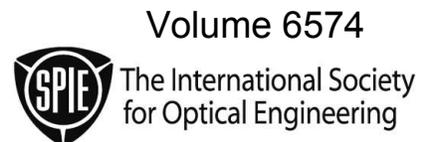
# PROCEEDINGS OF SPIE

## *Optical Pattern Recognition XVIII*

**David P. Casasent**  
**Tien-Hsin Chao**  
*Editors*

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